

FDS8934A

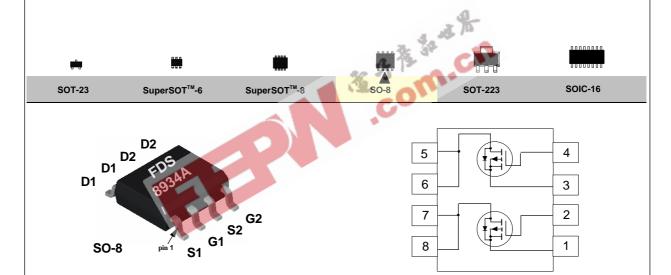
Dual P-Channel Enhancement Mode Field Effect Transistor

General Description

SO-8 P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- = -4 A , -20 V, R $_{\rm DS(ON)}$ = 0.055 Ω @ V $_{\rm GS}$ = -4.5 V, R $_{\rm DS(ON)}$ = 0.072 Ω @ V $_{\rm GS}$ = -2.5 V.
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.
- Dual MOSFET in surface mount package.

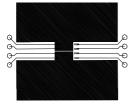


Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	FDS8934A	Units
V _{DSS}	Drain-Source Voltage	-20	V
V_{GSS}	Gate-Source Voltage	-8	V
I _D	Drain Current - Continuous (Note 1a)	- 4	А
	- Pulsed	-20	
P_{D}	Power Dissipation for Dual Operation	2	W
	Power Dissipation for Single Operation (Note 1a)	1.6	
	(Note 1b)	1	
	(Note 1c)	0.9	
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to 150	°C
THERMA	L CHARACTERISTICS		·
R _{ejja}	Thermal Resistance, Junction-to-Ambient (Note 1a)	78	°C/W
R _{eJC}	Thermal Resistance, Junction-to-Case (Note 1)	40	°C/W

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
Δ BV _{DSS} / Δ T _J	Breakdown Voltage Temp. Coefficient	I_D = -250 μ A, Referenced to 25 $^{\circ}$ C		-23		mV/°C
DSS	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, \ V_{GS} = 0 \text{ V}$			-1	μA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
ON CHARA	CTERISTICS (Note 2)		•		•	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-0.4	-0.6	-1	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I _D =-250 μA, Referenced to 25 °C		4		mV/°C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_{D} = -4 \text{ A}$		0.043	0.055	Ω
		T _J =125°C		0.062	0.077	
		$V_{GS} = -2.5 \text{ V}, I_D = -3.4 \text{ A}$		0.059	0.072	
D(ON)	On-State Drain Current	$V_{GS} = -10 \text{ V}, \ V_{DS} = -5 \text{ V}$	-20			Α
9 _{FS}	Forward Transconductance	$V_{DS} = -10 \text{ V}, I_{D} = -4 \text{ A}$		13		S
DYNAMIC	CHARACTERISTICS	3, 25, 10				
C _{iss}	Input Capacitance	$V_{DS} = -10 \text{ V}, \ V_{GS} = 0 \text{ V},$	A	1130		pF
oss	Output Capacitance	t = 1.0 MHz		480		pF
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = -10 \text{ V}, \ I_{D} = -4 \text{ A}$ $V_{DS} = -10 \text{ V}, \ V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$		120		pF
SWITCHING	G CHARACTERISTICS (Note 2)					
D(on)	Turn - On Delay Time	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ A}$		8	16	ns
r	Turn - On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		23	37	
D(off)	Turn - Off Delay Time			260	360	
f	Turn - Off Fall Time			90	125	
Q_g	Total Gate Charge	$V_{DS} = -5 \text{ V}, \ I_{D} = -4 \text{ A},$		20	28	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -5 V		2.8		
Q_{gd}	Gate-Drain Charge		<u> </u>	3.2		
DRAIN-SOL	JRCE DIODE CHARACTERISTICS AND MAX	IMUM RATINGS	,	1	,	
s	Maximum Continuous Drain-Source Diode Forward Current				-1.3	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{S} -1.3 \text{ A} \text{ (Note 2)}$		-0.7	-1.2	V

^{1.} $R_{\mu\mu}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\mu\nu}$ is guaranteed by design while $\boldsymbol{R}_{\boldsymbol{\theta}^{CA}}$ is determined by the user's board design.



a. 78°C/W on a 0.5 in² pad of 2oz copper.





c. 135°C/W on a 0.003 in² pad of 2oz copper.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics

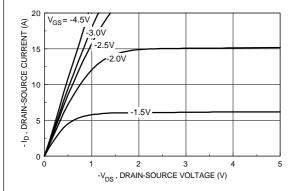


Figure 1. On-Region Characteristics.

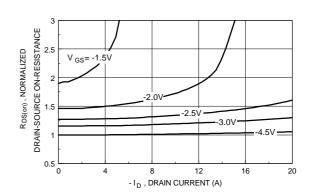


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

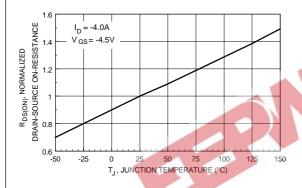


Figure 3. On-Resistance Variation with Temperature.

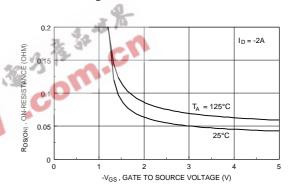


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

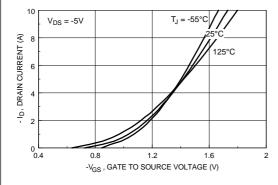


Figure 5. Transfer Characteristics.

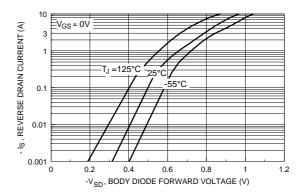
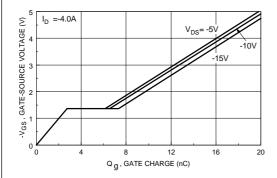


Figure 6. Body Diode Forward Voltage
Variation with Source Current
and Temperature.

Typical Electrical Characteristics (continued)



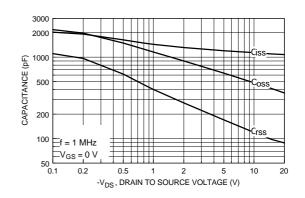
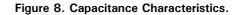
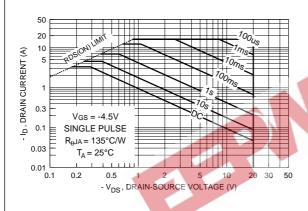


Figure 7. Gate Charge Characteristics.





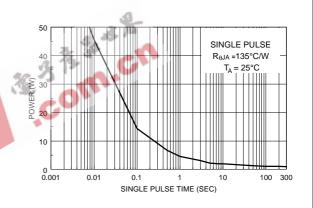


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

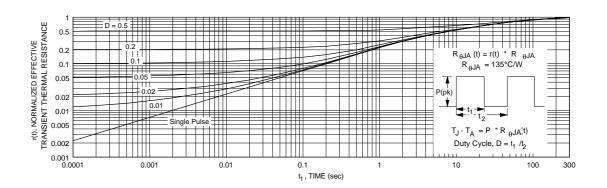
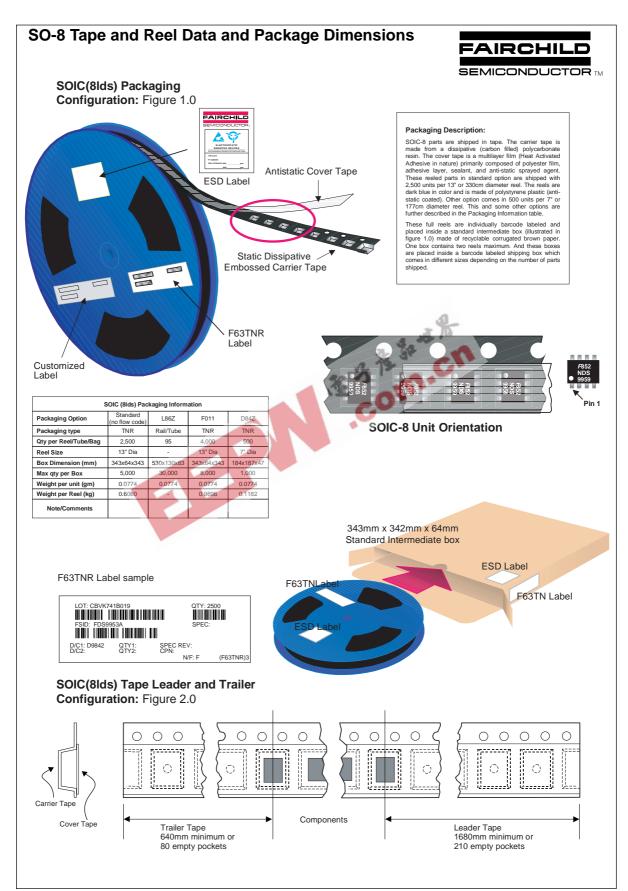
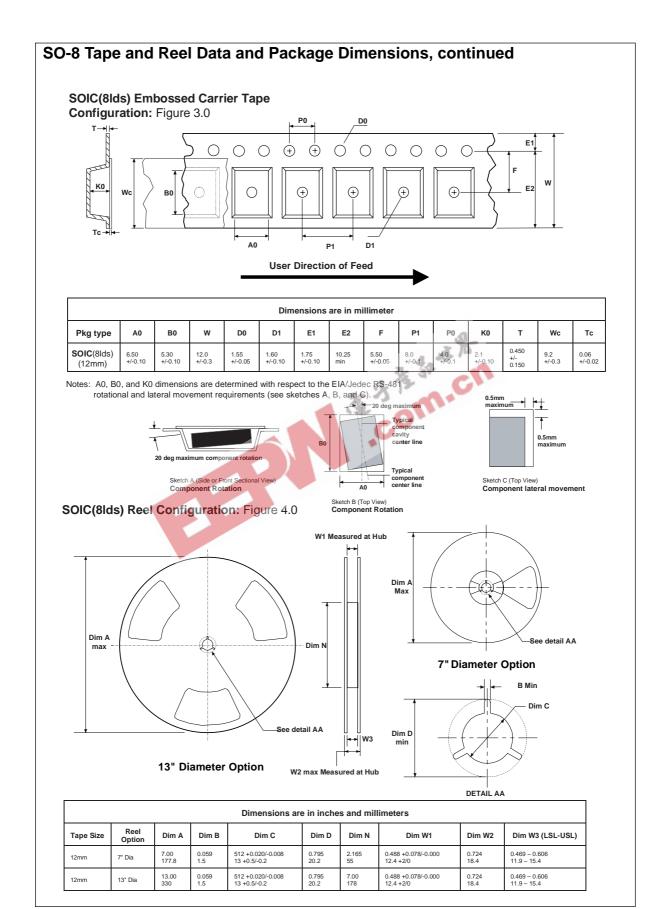
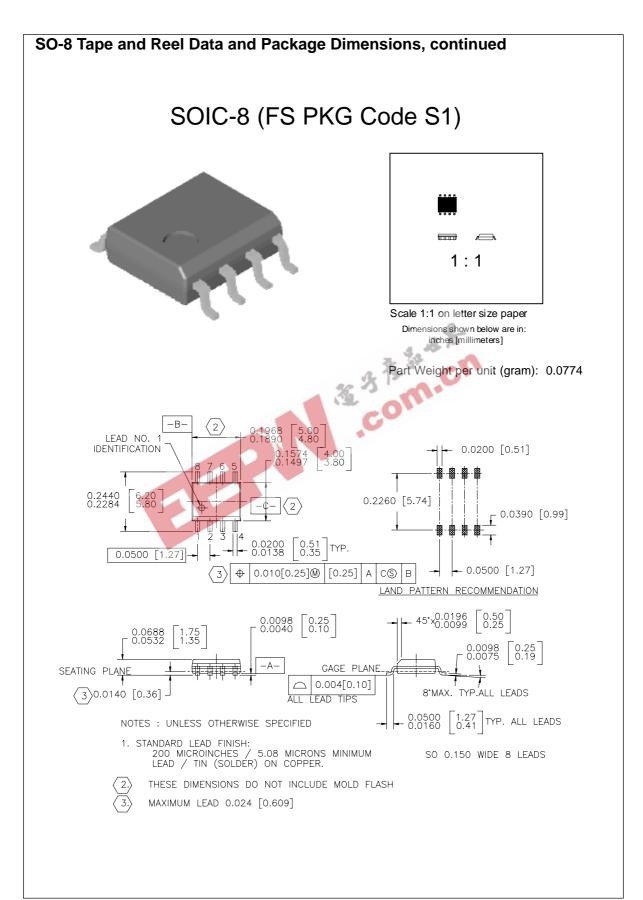


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.







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